Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/705,238	JANG ET AL.	
Examiner	Art Unit	
Matthew G. Kayrish	2627	

	SEAR	CHED	
Class	Subclass	Date	Examiner
	·		

INI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
		·· <u> </u>	-

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EASt (See Attached Search History)	4/2/2007	МК
		w